## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination DECKERS ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,744,625	06-2004	Syring et al.	361/685
	В	US-6,094,342 A	07-2000	Dague et al.	361/685
	С	US-6,456,501 B1	09-2002	Rubenstein et al.	361/759
	D	US-6,711,011 B2	03-2004	Lee, Myoung-ku	361/685
	E	US-5,680,293	10-1997	McAnally et al.	361/685
	F	US-6,275,382 B1	08-2001	Siedow et al.	361/727
	G	US-5,828,547 A	10-1998	Francovich et al.	361/685
	Н	US-5,682,291	10-1997	Jeffries et al.	361/685
	ı	US-6,496,363 B1	12-2002	Li, Chun-Liang	361/685
	J	US-6,590,775 B2	07-2003	Chen, Yun Lung	361/725
	к	US-6,757,164	06-2004	Lin, Chin-Tang	361/685
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
	N				·	·	
	0						
	Р			•			
	a						
	R			•			
	s						
	Т	·					

## **NON-PATENT DOCUMENTS**

NOTE ATENT DOCUMENTO								
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	v							
	w							
	х							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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